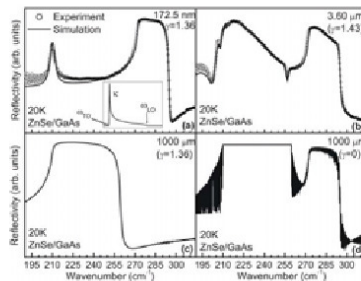
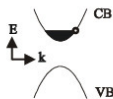




Kapil Chandra Agarwal (Autor)  
**Infrared Spectroscopic Investigations on II-VI Semi-Magnetic Semiconductors**  
(with 53 Figures)

Kapil Chandra Agarwal

Infrared Spectroscopic Investigations  
on  
II-VI Semi-Magnetic Semiconductors



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# Contents

<b>1</b>	<b>Introduction</b>	<b>1</b>
1.1	Technological interests .....	1
1.2	Our work .....	3
<b>2</b>	<b>Diluted magnetic semiconductor - (Zn, Mn)Se</b>	<b>5</b>
2.1	Introduction .....	5
2.2	Diluted magnetic semiconductors .....	6
2.3	ZnSe-based DMS.....	7
2.4	Crystal structure and lattice parameter.....	8
2.5	Band structure - ZnSe .....	12
2.5.1	Excitons in bulk ZnSe.....	14
2.6	Effect of manganese in $Zn_{1-x}Mn_xSe$ .....	15
2.6.1	Band-structure modifications in $Zn_{1-x}Mn_xSe$ .....	15
2.6.2	Energy-gap and negative bowing.....	16
2.6.3	Spin-orbit splitting energy ( $\Delta_{so}$ ).....	16
2.6.4	Index of refraction (n), Elastic constants, & Exciton binding energy..	17
2.6.5	Mn intra-ion transitions.....	18
2.6.6	Exchange interaction ( <i>s-d</i> and <i>p-d</i> or <i>sp-d</i> type).....	18
2.7	Zn(Mn)Se in spintronic and other device applications.....	19
<b>3</b>	<b>Experimental techniques</b>	<b>23</b>
3.1	Introduction .....	23
3.2	Fourier transform infrared spectroscopy.....	24
3.2.1	Working Principle of FT-IR Spectrometer.....	24
3.2.2	Why FT-IR Spectroscopy?.....	30
3.2.3	The Fourier Transformation.....	33
3.2.4	Apodization.....	35
3.2.5	Zero Filling.....	38
3.2.6	Precise measurement of the optical path difference (OPD).....	39

## Contents

---

3.2.7	Sampling and over-sampling of the interferogram.....	40
3.2.8	FT-IR instruments have a short wavelength $\lambda$ (high energy) limit.....	41
3.2.9	Frictionless floating of the scanner.....	42
3.3	Experimental details for optical measurements.....	43
3.4	Electrical characterization - Hall measurements.....	53
3.5	Ellipsometry measurements.....	55
<b>4</b>	<b>Samples</b>	<b>59</b>
4.1	Introduction .....	59
4.2	Sample growth .....	60
4.3	Sample structure.....	61
4.4	Thickness determination.....	63
4.5	Manganese content determination.....	64
4.6	Sample preparation.....	65
4.7	Sample details.....	67
<b>5</b>	<b>Electron effective mass in Zn(Mn)Se:Cl</b>	<b>69</b>
5.1	Introduction .....	69
5.2	Electron effective mass .....	70
5.3	Theoretical considerations.....	71
5.4	Determination of electron effective mass .....	75
5.4.1	Data Analysis.....	75
5.4.2	Determination of free-electron concentration.....	79
5.4.3	Infrared reflection (plasma-edge) measurements.....	80
5.4.4	Magneto-optical generalized ellipsometry (MOGE) results.....	90
5.5	Summary.....	93
<b>6</b>	<b>Phonon properties of Zn(Mn)Se</b>	<b>95</b>
6.1	Introduction .....	95
6.2	Phonon modes in ZnSe.....	96
6.3	Phonon modes in ternary alloys like $Zn_{1-x}Mn_xSe$ .....	96
6.4	Dielectric response model for $Zn_{1-x}Mn_xSe$ .....	99
6.5	Phonon properties in $Zn_{1-x}Mn_xSe$ ( $0 \leq x \leq 0.43$ ).....	102
6.6	Dielectric constant in ZnSe .....	108
6.7	Thickness effects in layered media .....	109
6.8	Summary.....	111
<b>7</b>	<b>Summary and Outlook (Zusammenfassung und Ausblick)</b>	<b>113 (117)</b>

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Contents

---

<b>List of own publications</b>	<b>121</b>
<b>List of figures</b>	<b>125</b>
<b>List of tables</b>	<b>131</b>
<b>Bibliography</b>	<b>133</b>
<b>Acknowledgments</b>	<b>141</b>
<b>Curriculum vitae</b>	<b>145</b>